

**Search Notes**

Application/Control No.

10/627,779

Examiner

Leon J. Harper

Applicant(s)/Patent under  
Reexamination

NAGANO ET AL.

Art Unit

2166

**SEARCHED**

Class	Subclass	Date	Examiner
707	104.1, 1, 100, 10, 102	1/18/2006	LJH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR